

N-CHANNEL 600V - 0.098Ω - 40A ISOTOP PowerMesh™II MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STE40NC60	600V	< 0.13Ω	40 A

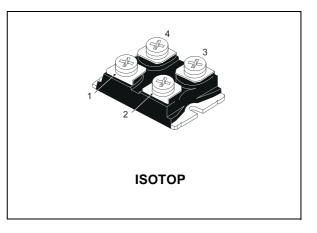
- TYPICAL $R_{DS}(on) = 0.098 \Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
 400% AV(ALANCUE TESTED
- 100% AVALANCHE TESTED
- NEW HIGH VOLTAGE BENCHMARK
- GATE CHARGE MINIMIZED

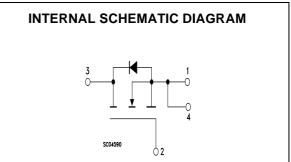
DESCRIPTION

The PowerMESHTMII is the evolution of the first generation of MESH OVERLAYTM. The layout refinements introduced greatly improve the Ron*area figure of merit while keeping the device at the leading edge for what concerns swithing speed, gate charge and ruggedness.

APPLICATIONS

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVER





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage ($V_{GS} = 0$)	600	V
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	600	V
V _{GS}	Gate- source Voltage	±30	V
Ι _D	Drain Current (continuos) at T _C = 25°C	40	Α
I _D	Drain Current (continuos) at T _C = 100°C	23	Α
I _{DM} (•)	Drain Current (pulsed)	160	Α
P _{TOT}	Total Dissipation at $T_C = 25^{\circ}C$	460	W
	Derating Factor	3.68	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	3	V/ns
VISO	Insulation Winthstand Voltage (AC-RMS)	2500	V
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C
)Pulse width li Iay 2002	mited by safe operating area	(1) I _{SD} ≤ 40A, di/dt≤100 A/μs, V _{DD} ≤ 24V, Tj≤T _{jMAX}	1/8

THERMAL DATA

Rthj-case	Thermal Resistance Junction-case	Max	0.272	°C/W
Rthc-h	Thermal Resistance Case-heatsink with C Grease Applied	Conductive	0.05	°C/W

AVALANCHE CHARACTERISTICS

Symbol	Parameter	Max Value	Unit
I _{AR}	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max)	40	A
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	1150	mJ

ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0	600			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating, T _C = 125 °C			10 100	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	$V_{GS} = \pm 30V$			±100	nA

ON (1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10V, I _D = 20A		0.098	0.130	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (1)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max,}$ $I_{D} = 15 \text{ A}$		42		S
Ciss	Input Capacitance	$V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$		11.1		nF
Coss	Output Capacitance			1190		pF
C _{rss}	Reverse Transfer Capacitance			100		pF

Note: 1. Pulsed: Pulse duration = $300 \ \mu$ s, duty cycle 1.5 %.

ELECTRICAL CHARACTERISTICS (CONTINUED)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on Delay Time	$V_{DD} = 300 \text{ V}, I_D = 20 \text{ A}$		49		ns
tr	Rise Time	$R_G = 4.7\Omega V_{GS} = 10V$ (see test circuit, Figure 3)		42		ns
Qg	Total Gate Charge	$V_{DD} = 480V, I_D = 40A,$		307.5	430	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10V		48		nC
Q _{gd}	Gate-Drain Charge			146.5		nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{r(Voff)}	Off-voltage Rise Time	$V_{DD} = 480V, I_D = 40A,$		41		ns
t _f	Fall Time	$R_G = 4.7\Omega, V_{GS} = 10V$ (see test circuit, Figure 5)		26		ns
t _c	Cross-over Time			74		ns

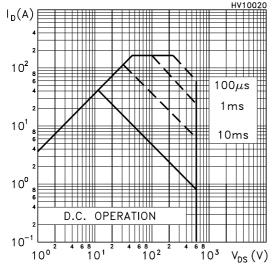
SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain Current				40	А
I _{SDM} (2)	Source-drain Current (pulsed)				160	А
V _{SD} (1)	Forward On Voltage	$I_{SD} = 40A, V_{GS} = 0$			1.6	V
t _{rr}	Reverse Recovery Time	I _{SD} = 40 A, di/dt = 100 A/µs,		685		ns
Qrr	Reverse Recovery Charge	V _{DD} = 40 V, T _j = 150 °C (see test circuit, Figure 5)		15		μC
I _{RRM}	Reverse Recovery Current			44		А

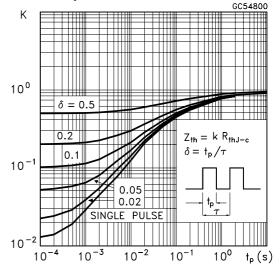
 Note:
 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.

 2. Pulse width limited by safe operating area.

Safe Operating Area

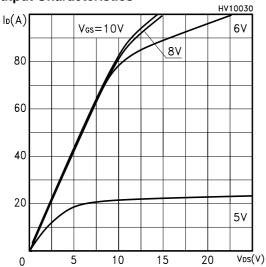


Thermal Impedence

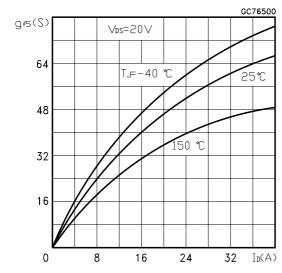


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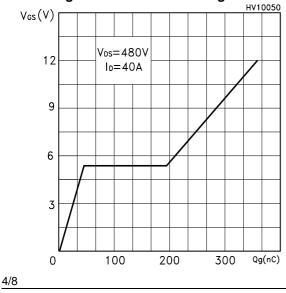
Output Characteristics



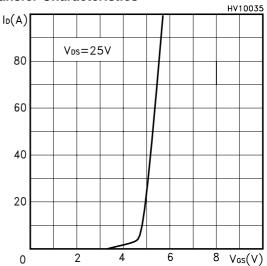
Transconductance



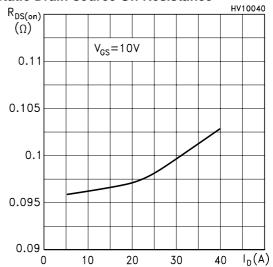
Gate Charge vs Gate-source Voltage

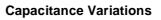


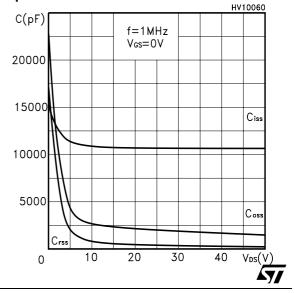
Transfer Characteristics

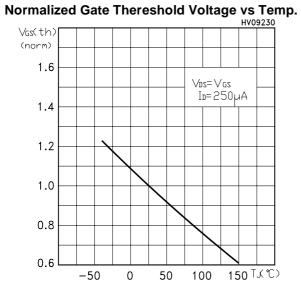


Static Drain-source On Resistance

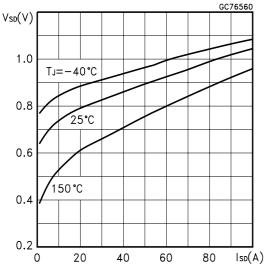






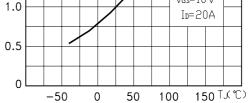


Source-drain Diode Forward Characteristics



Ros(on) (norm) 2.5 2.0 1.5 VGs=10∨ 1.0

Normalized On Resistance vs Temperature



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Fig. 1: Unclamped Inductive Load Test Circuit

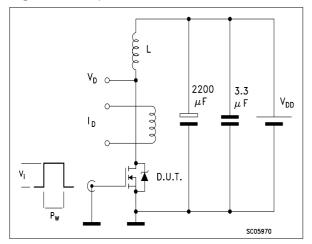


Fig. 3: Switching Times Test Circuit For Resistive Load

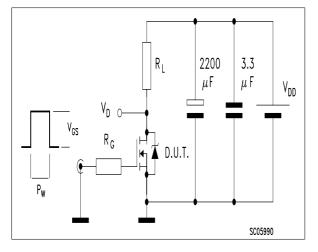
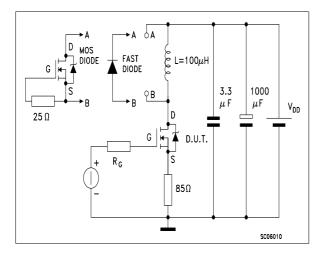


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



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Fig. 2: Unclamped Inductive Waveform

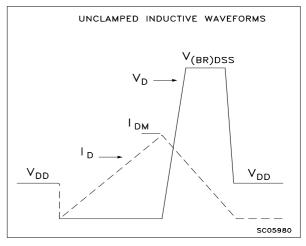
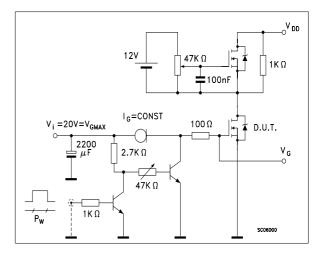


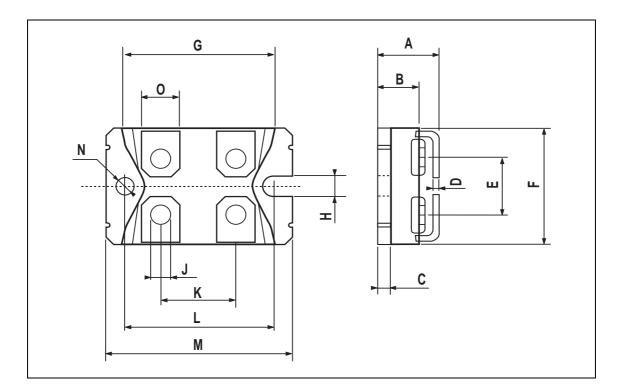
Fig. 4: Gate Charge test Circuit





DIM.		mm		inch			
Diwi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	11.8		12.2	0.466		0.480	
В	8.9		9.1	0.350		0.358	
С	1.95		2.05	0.076		0.080	
D	0.75		0.85	0.029		0.033	
E	12.6		12.8	0.496		0.503	
F	25.15		25.5	0.990		1.003	
G	31.5		31.7	1.240		1.248	
Н	4			0.157			
J	4.1		4.3	0.161		0.169	
К	14.9		15.1	0.586		0.594	
L	30.1		30.3	1.185		1.193	
М	37.8		38.2	1.488		1.503	
Ν	4			0.157			
0	7.8		8.2	0.307		0.322	

ISOTOP MECHANICAL DATA



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